Search Notes			

Applicat	ion/Control No.	Applicant(s)/Patent Reexamination	under
09/961,0	026	MCQUAIN, BARR	Υ .
Examine	er ·	Art Unit	
Sara Ch	andler	3693	

SEARCHED			
Class	Subclass	Date	Examiner
705	37	9/21/2007	SMC
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
705	37	9/21/2007	SMC
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